Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/643,777	AN, WEI	
Examiner	Art Unit	
Chuona D. Nao	2193	

SEARCHED				
Class	Subclass	Date	Examiner	
708	252	3/8/2007	CN	
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375	149	V	1	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
708	252	11/28/2007	CN	
375	149	V		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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